

Design Verification and Test of Digital VLSI Circuits - Video course

COURSE OUTLINE

Digital VLSI Design flow comprises three basic phases: Design, Verification and Test. The video course would cover theoretical, implementation and CAD tools pertaining to these three phases. Although there can be individual full courses for each of these phases, the present course aims at covering the important problems/algorithms/tools so that students get a comprehensive idea of the whole digital VLSI design flow.

VLSI Design: High level Synthesis, Verilog RTL Design, Combinational and Sequential Synthesis Logic Synthesis (for large circuits).

Verification Techniques: Introduction to Hardware Verification and methodologies, Binary Decision Diagrams(BDDs) and algorithms over BDDs, Combinational equivalence checking, Temporal Logics, Modeling sequential systems and model checking, Symbolic model checking.

VLSI Testing: Introduction, Fault models, Fault Simulation, Test generation for combinational circuits, Test generation algorithms for sequential circuits and Built in Self test.

COURSE DETAIL

S.No	Details
1.	<u>Design</u>
	Module I: Introduction Lecture I: Introduction to Digital VLSI Design Flow Lecture II: High Level Design Representation Lecture III: Transformations for High Level Synthesis
	Module II: Scheduling, Allocation and Binding Lecture I: Introduction to HLS: Scheduling, Allocation and Binding Problem Lecture II and III: Scheduling Algorithms Lecture IV: Binding and Allocation Algorithms
2.	Module III: Logic Optimization and Synthesis Lecture I,II and III: Two level Boolean Logic Synthesis Lecture IV: Heuristic Minimization of Two-Level Circuits Lecture V: Finite State Machine Synthesis Lecture VI: Multilevel Implementation
	<u>Verification</u>

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**Computer
Science and
Engineering**

Pre-requisites:

1. Digital Design
2. Algorithm
3. Automata Theory (Basics)

Coordinators:

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Module - IV: Temporal Logic

Lecture-I: Introduction to formal methods for verification
 Lecture-II: Temporal Logic: Introduction and Basic Operators
 Lecture-III: Syntax and Semantics of CTL
 Lecture IV: Equivalence between CTL Formulas

Module - V: Binary Decision Diagram

Lecture-I: Binary Decision Diagram: Introduction and construction
 Lecture-II: Ordered Binary Decision Diagram
 Lecture-III: Operations on Ordered Binary Decision Diagram
 Lecture-IV: Ordered Binary Decision Diagram for Sequential Circuits

Module-VI: Verification Techniques

Lecture-I: Introduction to Verification Techniques
 Lecture-II and III: Model Checking
 Lecture-IV and V: Symbolic Model Checking

3.

Test**Module VII: Introduction to Digital Testing**

Lecture-I: Introduction to Digital VLSI Testing
 Lecture-II: Functional and Structural Testing
 Lecture-III: Fault Equivalence

Module VIII: Fault Simulation and Testability Measures

Lecture-I, II and III: Fault Simulation
 Lecture-IV: Testability Measures (SCOAP)

Module IX: Combinational Circuit Test Pattern Generation

Lecture-I: Introduction to Automatic Test Pattern Generation (ATPG) and ATPG
 Algebras
 Lecture-II and III: D-Algorithm

Module X: Sequential Circuit Testing and Scan Chains

Lecture-I: ATPG for Synchronous Sequential Circuits
 Lecture-II and III: Scan Chain based Sequential Circuit Testing

Module XI: Built in Self test (BIST)

Lecture I and II: Built in Self Test
 Lecture III and IV: Memory Testing

References:

1. D. D. Gajski, N. D. Dutt, A.C.-H. Wu and S.Y.-L. Lin, High-Level Synthesis: Introduction to Chip and System Design, Springer, 1st edition, 1992.
2. S. Palnitkar, Verilog HDL: A Guide to Digital Design and Synthesis, Prentice Hall, 2nd edition, 2003.

3. G. De Micheli. Synthesis and optimization of digital circuits, 1st edition, 1994.
4. M. Huth and M. Ryan, Logic in Computer Science modeling and reasoning about systems, Cambridge University Press, 2nd Edition, 2004
5. Bushnell and Agrawal, Essentials of Electronic Testing for Digital, Memory & Mixed-Signal Circuits, Kluwer Academic Publishers, 2000